

DCMTK - Feature #258

Test pattern with overlay in LSB

2007-01-12 00:00 - Marco Eichelberg

Status:	New	Start date:	
Priority:	Low	Due date:	
Assignee:		% Done:	0%
Category:		Estimated time:	0:00 hour
Target version:		Compiler:	
Module:	dcmdata/dcmcheck		
Operating System:			
Description			
Develop sample test pattern that contains an overlay in the pixel data LSB (e.g. bitAllocated=16, bitsStored=12, highBit=11 aber DENNOCH overlayBit=0, d.h. das "Rauschen" in den Bilddaten ist gleichzeitig ein Overlay.)			